## Notice of References Cited Application/Control No. 09/986,814 Examiner LE NGUYEN Applicant(s)/Patent Under Reexamination MCLEAN ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,481,741	01-1996	McKaskle et al.	345/522
*	В	US-5,504,917	04-1996	Austin, Paul F.	345/522
*	С	US-5,301,301	04-1994	Kodosky et al.	716/11
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	National Instruments, September 2000, LabVIEW Basics II Course Manual (pages 1-276)			
	V				
	w				
	x				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.